Sear	ch No	otes	

Application/Control No.	Applicant(s)/Patent under Reexamination
09/847,056	TAKATZ ET AL.
Examiner	Art Unit
Ted M. Wang	2634

	SEARCHED		
Class	Subclass	Date	Examiner
375	316	12/7/2005	TW
455	136,138	12/7/2005	TW
455	239.1	12/7/2005	TW
455	245.1	12/7/2005	TW
455	247.1	12/7/2005	TW
	UPDATED		
375	345	12/7/2005	TW
455	234.1	12/7/2005	TW

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
375	345,316	12/7/2005	TW
455	136,138	12/7/2005	TW
455	234.1	12/7/2005	TW
455/239.1,2	245.1,247.1	12/7/2005	TW

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST - USPGPUB, USPAT, USOCR, EPO, JPO, DERWENT, IBM_TDB, see attached search report	12/7/2005	TW
IEEE - Advance search -RF and AGC and variable gain control and amplifier and comparator and ADC	12/7/2005	TW
IEEE - Advance search- narrow band and wide band and comparator and AGC and gain control	12/7/2005	TW
Google -RF and AGC and narrow band and wideband and variable gain control and amplifier and comparator and ADC	12/7/2005	TW